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Supporting information for article:

Beam and sample movement compensation for robust spectro-microscopy measurements on a hard X-ray nanoprobe

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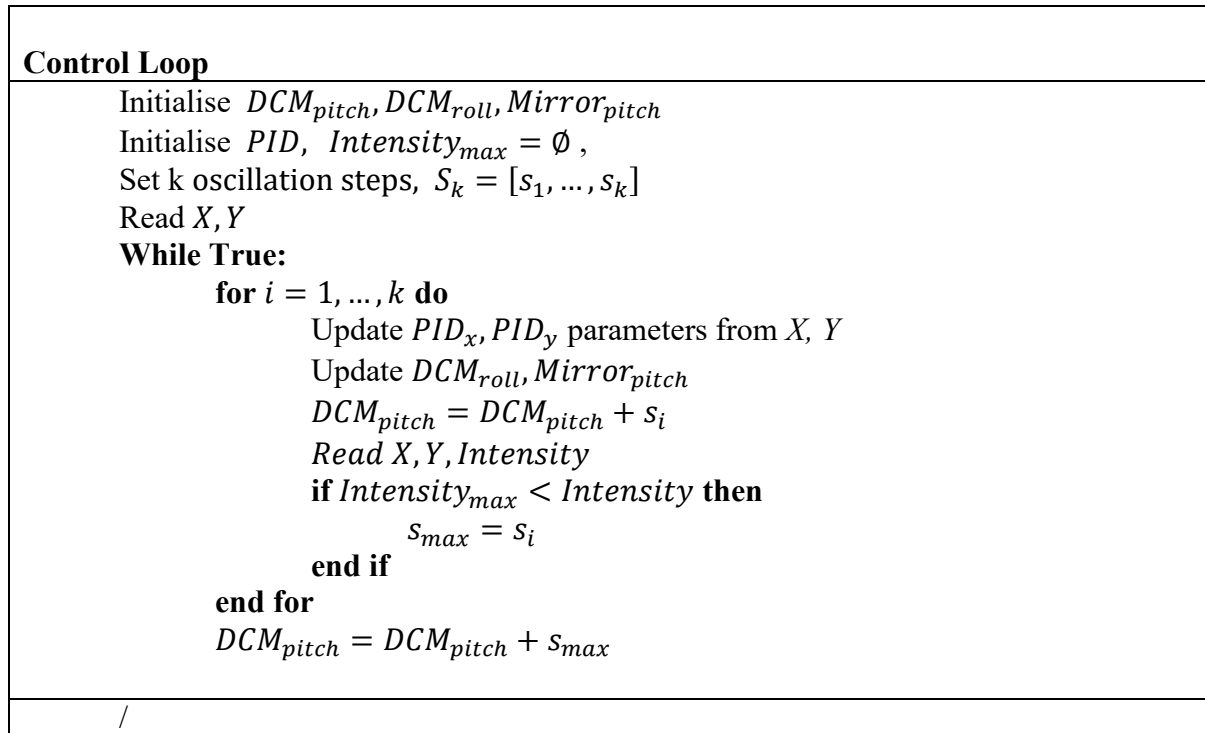


Figure S1 Control Loop used for maximizing intensity and setting the X, Y beam position.